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43	BRS 11	(barcode dataform symbology ((bar optical readable) adj1 (code label indicia symbol)) near5 (scan\$4 read\$3 terminal) same (internet (world adj wide adj3 web) www html (hypertext pos (point adj1 sale) kiosk (check adj out)) checkout		EPO; JPO; DERWENT; IBM_TDB	2003/04/05 18:55	0
44	BRS 2	(6456981.pn. 5950173.pn. 5754655.pn. 6502749.pn. 6539422.pn. 20010020641.pn. 5256863.pn. 5886336.pn. 5924079.pn. 6237852.pn. 6241149.pn.) and (ethernet nic (network adj1 card))	USPAT; US_PGPUB	2003/04/05 19:21		0
45	BRS 35	(barcode dataform symbology ((bar optical readable) adj1 (code label indicia symbol)) near5 (scan\$4 read\$3 terminal) pos (point adj1 sale) checkout (check adj out)) near5 (scale weigh\$3) near5 (keypad keyboard input\$3)	USPAT; US_PGPUB	2003/04/05 20:03		0
46	BRS 11	(barcode dataform symbology ((bar optical readable) adj1 (code label indicia symbol)) near5 (scan\$4 read\$3 terminal) pos (point adj1 sale) checkout (check adj out)) near5 (scale weigh\$3) near5 (keypad keyboard input\$3)	EPO; JPO; DERWENT; IBM_TDB	2003/04/05 20:07		0
47	BRS 37	705/416.ccls.	USPAT; US_PGPUB	2003/04/05 20:23		0

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48	BRS	223	177/25.15.cc1s.	USPAT; US-PGPUB	2003/04/05 20:24			0

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**1 Information technology and product lifecycle management**  
*Thomas, V.; Neckel, W.; Wagner, S.;*  
Electronics and the Environment, 1999. ISEE -1999. Proceedings of the 1999 IEEE International Symposium on, 1999  
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